

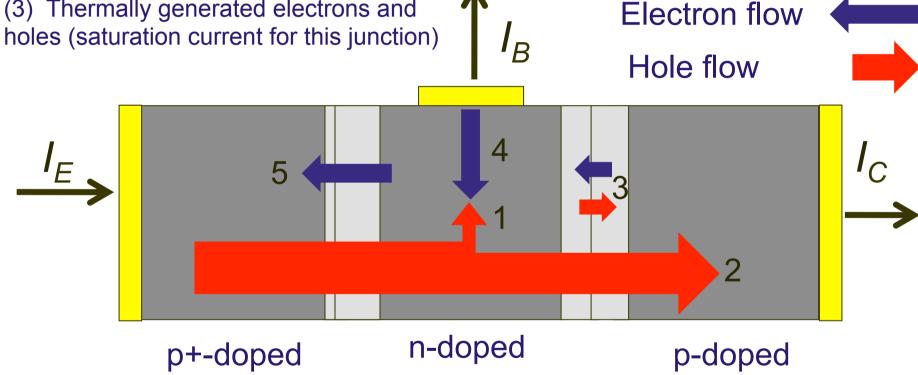
#### Lecture 18

- Bipolar Junction Transistor
- Operation Bias and Currents
- Current gain
- Application as amplifier
- Characteristics, Load Line



#### Bipolar Transistor Current flow Summary

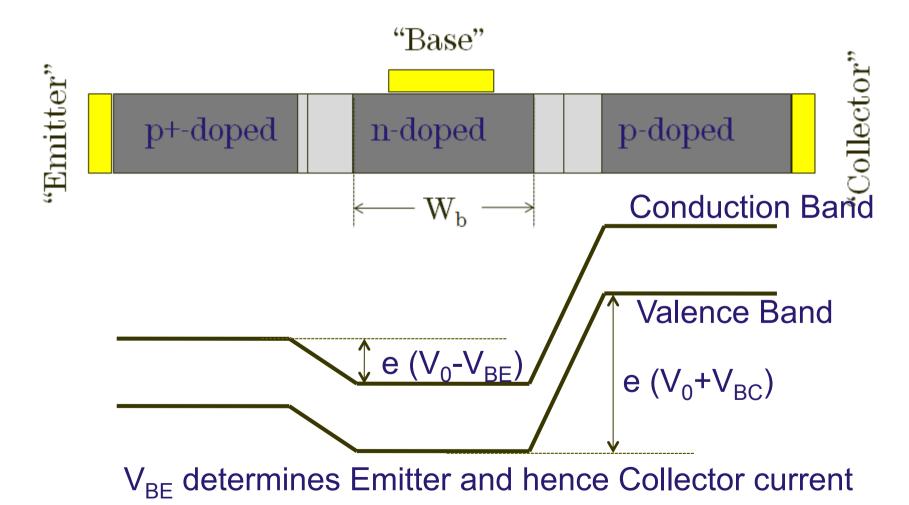
- (1) Injected holes lost to recombination in n-type base
- (3) Thermally generated electrons and
- (2) Injected holes which reach the reverse biased collector junction



- (4) Electrons supplied to replace those lost by recombination with holes in the base
- (5) Electrons injected across the forward biased emitter junction

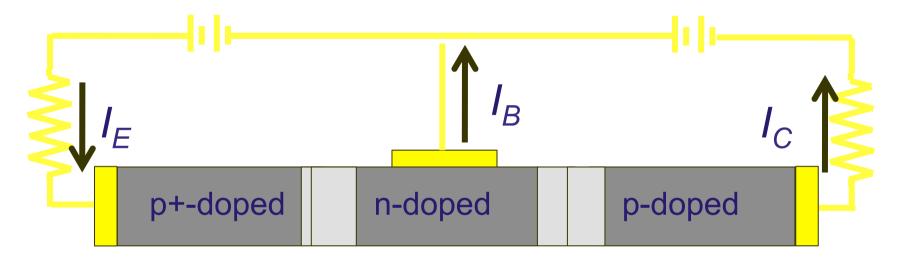


### Operational Bias – p+-n-p



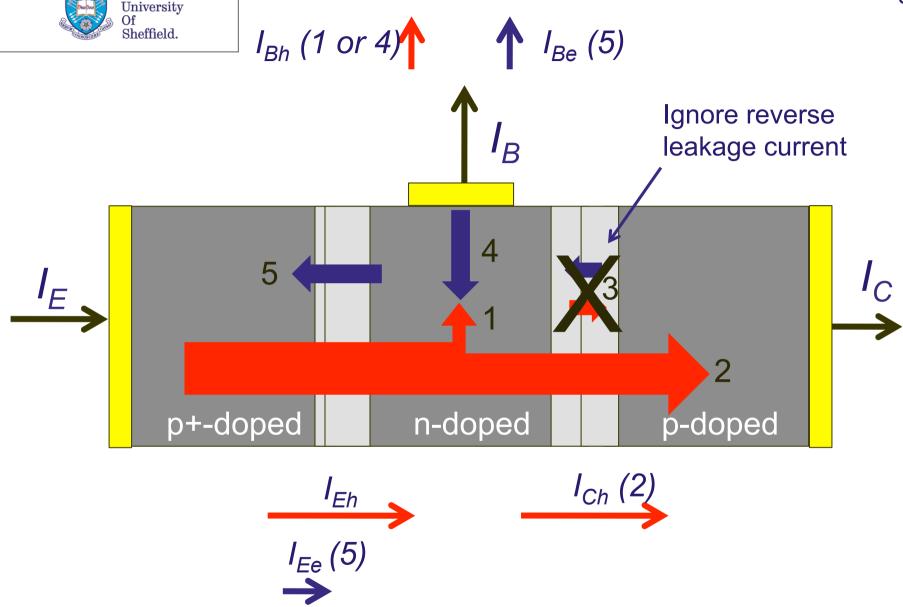


#### **Terminal Currents**



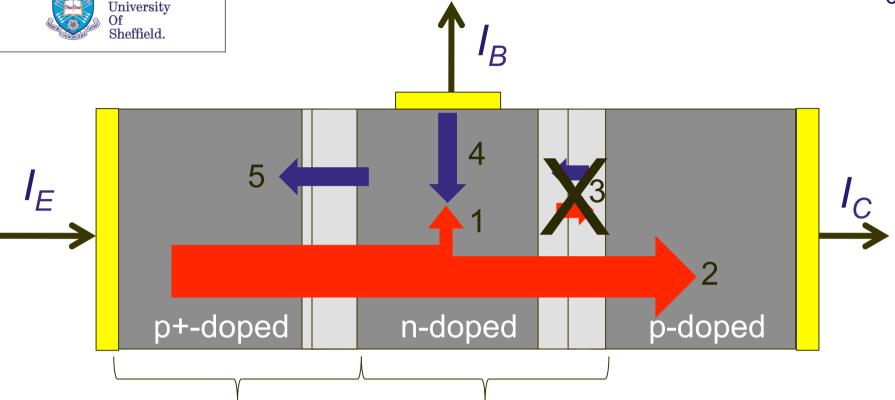
- Ideally  $I_E \approx I_C$  and  $I_B$  is small
- Amplification is from comparing  $I_B$  to  $I_E$  or  $I_C$
- We can derive relationships for ratios of these three currents











#### **Emitter efficiency**

- fraction of emitter current due to holes (or electrons in n<sup>+</sup>-p-n devices)

$$\gamma = \frac{I_{Eh}}{I_{Ee} + I_{Eh}}$$

 $I_C = B I_{Fh}$ 

**B** - Base transport factor – fraction of holes from the emitter which reach the collector

For a high gain transistors both need to be very close to 1



# Terminal Currents (2)

Ratio of 
$$I_E$$
 and  $I_C$   $\frac{I_C}{I_E} = \frac{BI_{Eh}}{I_{Ee} + I_{Eh}} = B\gamma = \alpha \approx 1$ 

 $\alpha$  is the **current transfer ratio** between the emitter and collector and is slightly less than 1 i.e. ~0.99

Base current 
$$I_B = I_{Ee} + (1-B)I_{Eh}$$

Ratio of 
$$I_B$$
 and  $I_C$  (current gain) 
$$\frac{I_C}{I_B} = \frac{BI_{Eh}}{I_{Ee} + (1 - B)I_{Eh}}$$



# The University Of Sheffield. Terminal Currents (3)

Expand by using previous equations and divide top and bottom by total emitter current

$$\frac{I_C}{I_B} = \frac{BI_{Eh}}{I_{Ee} + (1-B)I_{Eh}} = \frac{B(I_{Eh}/I_{Ee} + I_{Eh})}{(I_{Ee}/I_{Ee} + I_{Eh}) + (1-B)(I_{Eh}/I_{Ee} + I_{Eh})}$$

Cancel terms and then substitute for y

$$\frac{I_C}{I_B} = \frac{B \left[\frac{I_{Eh}}{I_{Ee} + I_{Eh}}\right]}{1 - B \left[\frac{I_{Eh}}{I_{Ee} + I_{Eh}}\right]} = \frac{B\gamma}{1 - B\gamma} = \frac{\alpha}{1 - \alpha} \equiv \beta$$

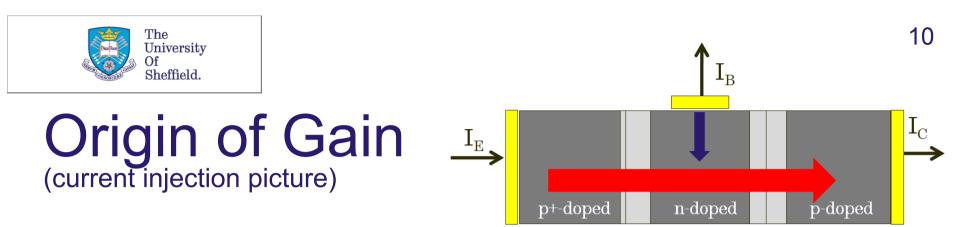
- $\beta$  is the **current gain** or current amplification factor
- Since  $B\gamma = \alpha \sim 1$ ,  $\beta$  can be large (typically up to 100)



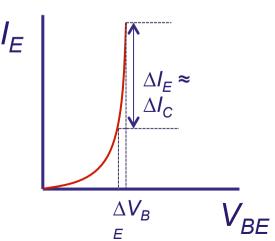
#### Current Gain, $\beta$

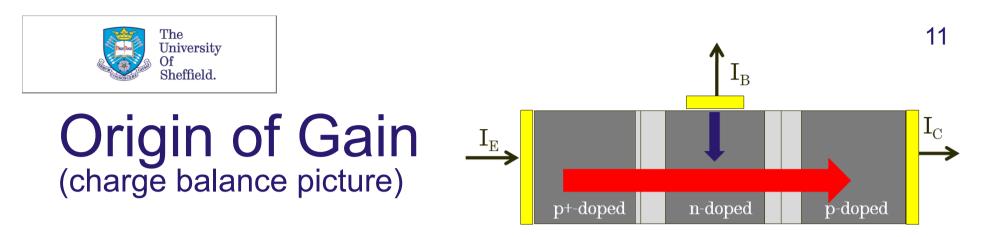
The expression for the current gain,  $\beta$ , indicates that we need the E-B current to consist mainly of majority carriers from the emitter (defined by the emitter efficiency  $\gamma$  - need p<sup>+</sup>>>n in a p<sup>+</sup>-n-p device or  $n^+$ >>p in a n<sup>+</sup>-p-n device) and that most of these majority carriers reach the collector without recombining in the base (defined by base transport factor, B – length of the base,  $L_B$ , must be much smaller than the minority carrier diffusion length,  $W_h$  (holes in this case))

e.g. if  $\gamma = 0.98$ , B = 0.95, current gain,  $\beta = 0.98 \times 0.95/(1-0.98 \times 0.95) \sim 13.5$  if  $\gamma = 0.99$ , B = 0.995, current gain,  $\beta = 0.99 \times 0.995/(1-0.99 \times 0.995) \sim 66$ 



- In a similar way to gate bias controlling the output current in a FET so the E-B bias controls the collector current a small  $\Delta V_{BF}$  can control a large  $\Delta I_{C}$
- Hence voltage gain =  $(\Delta I_C R_L)/\Delta V_{BE}$  where  $R_L$  is the load resistor in the collector circuit
- Usually we use current gain =  $\frac{I_C}{I_B}$  and  $I_B$  depends on  $V_{BF}$
- Transconductance  $g_m = \frac{\Delta I_C}{\Delta V_{BE}}$





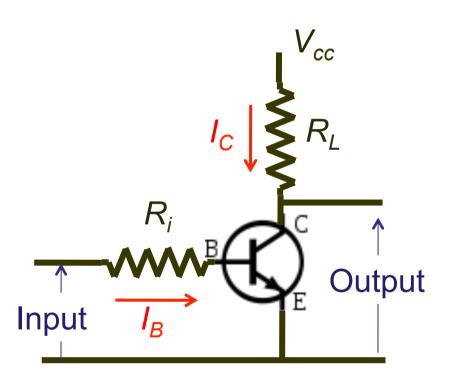
#### Assumes emitter efficiency $\gamma = 1$

- The base must remain neutral i.e. the free carrier density equals donor atom density
- Excess holes injected into the base spend a short time there they transit the base by diffusion in a time  $\tau_t$  (base transit time)
- To maintain neutrality while there are excess holes in the base an equal number of balancing excess electrons enter the base from the contact
- On average these excess electrons last for the same time as the lifetime of the holes in the base i.e.  $\tau_p$
- For each electron entering the base to balance the excess holes,  $\tau_p/\tau_t = \beta$  holes pass from emitter to collector i.e. get  $\beta$  holes traversing the base for every electron entering from the contact  $\rightarrow$  current gain



## Common Emitter Amplifier

(Up to now we have looked at common-base connection)



The base emitter is in  $\sim$ forward bias so gives  $V_{BE} \sim V_0$ 

Input voltage varies  $I_B$ 

$$\Delta I_C = \beta \Delta I_B$$

Important characteristics are  $V_{CE}$ ,  $I_{C}$ , and  $I_{B}$ 

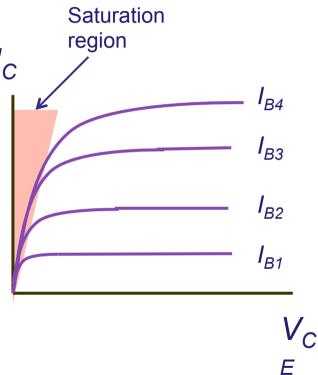


# Characteristics (common emitter connection) Saturation

$$V_{CF} = V_{CB} + V_{BF}$$

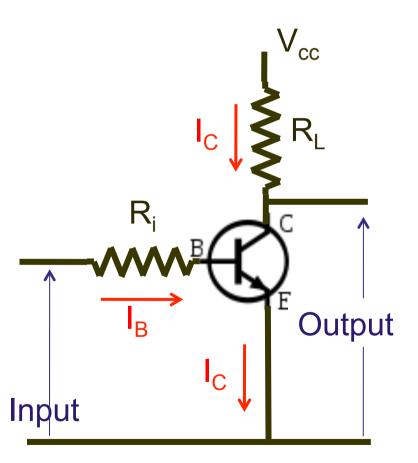
- Saturation region (note: different from FET!) both junctions in forward bias and  $V_{CB} \approx V_{BE}$  and  $V_{CE}$  small
- Remainder of region is "normal operation" where emitter-base forward biased and base-collector reverse biased

$$\Delta I_C = \beta \Delta I_B$$





## Common Emitter Amplifier (2)



$$V_{CC} = I_c R_L + V_{CE}$$

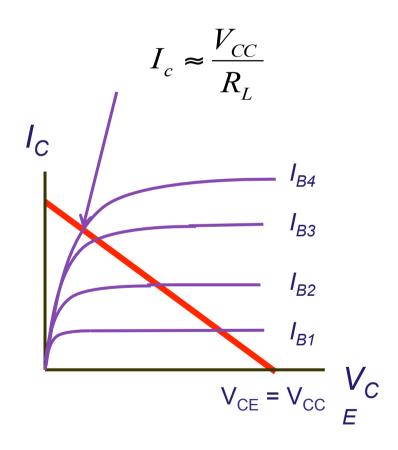
What are the bias extremes?

• 
$$I_C$$
=0 - device "off"  $\rightarrow V_{CE} = V_{CC}$ 

• 
$$V_{CE}$$
=0 - device "on"  $\rightarrow$   $I_c = \frac{V_{CC}}{R_L}$ 



#### **Load Line**





### Summary

- In bipolar transistors output (collector) current is controlled by injection from the emitter-base junction
- Current gain is affected by nature of emitter-base doping and the thickness of the base
- The common-emitter configuration acts as a current amplifier